

OptiMOS[™]-5 Power Transistor





Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Logic Level
- MSL1 up to 260°C peak reflow
- 175 °C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

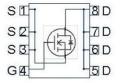
Product Summary

V_{DS}	100	٧
$R_{\mathrm{DS(on),max}}$	12	mΩ
I_{D}	40	Α

PG-TSDSON-8-33



Туре	Package	Marking
IAUZ40N10S5L120	PG-TSDSON-8-33	5N1L120



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Drain current	I _D	V _{GS} =10 V, Chip limitation ^{1,2)}	46	А
		V _{GS} =10V, DC current ³⁾	40	
		T_a =85 °C, V_{GS} =10 V, R_{thJA} on 2s2p $^{2,4)}$	9	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	160	
Avalanche energy, single pulse ²⁾	E _{AS}	I _D =20 A	33	mJ
Avalanche current, single pulse	IAS	-	22	Α
Gate source voltage	V _{GS}	-	±20	V
Power dissipation	P _{tot}	T _C =25 °C	62	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}	-	-	-	2.4	K/W
Thermal resistance, junction - ambient ⁴⁾	R _{thJA}	-	-	35.5	-	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, I _D =1mA	100	-	-	V
Gate threshold voltage	V _{GS(th)}	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=27~\mu{\rm A}$	1.2	1.7	2.2	
Zero gate voltage drain current	I _{DSS}	V _{DS} =100V, V _{GS} =0V, T _j =25°C	-	0.1	1	μA
		$V_{\rm DS}$ =100V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =20A	-	13.6	18.5	mΩ
		V _{GS} =10V, I _D =20A	-	10.3	12	
Gate resistance ²⁾	R _G	-	-	1.3	-	Ω



Parameter	Symbol Conditions	Values			Unit	
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	C iss		-	1222	1589	pF
Output capacitance	C oss	V _{GS} =0V, V _{DS} =50V, f=1MHz	-	213	277	1
Reverse transfer capacitance	C _{rss}]	-	12	18	
Turn-on delay time	t _{d(on)}		-	3	-	ns
Turn-off delay time	t _{d(off)}	V _{DD} =50V, V _{GS} =10V,	-	11	-	
Rise time	t _r	$I_D=20A$, $R_{G,ext}=3.5\Omega$	-	1	-	
Fall time	t _f		-	6	-	
Gate to drain charge	Q _{gs}	V _{DD} =50V, I _D =20A, V _{GS} =0 to 10V	-	3.8	4.9	nC
Gate to drain charge	Q _{gd}			3.3	5.0	
Gate charge total	Q _g		-	17.4	22.6	
Gate plateau voltage	V _{plateau}		-	3.1	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T _C =25°C	-	-	40	Α
Diode pulse current ²⁾	I _{S,pulse}	T _C =25 °C	-	-	160	
Diode forward voltage	V _{SD}	V _{GS} =0V, I _F =20 A, T _j =25°C	-	0.9	1.1	V
Reverse recovery time ²⁾	t _{rr}	V _R =50V, I _F =40A,	-	38	-	ns
	Q _{rr}	d <i>i</i> _F /d <i>t</i> =100A/μs		1		1

¹⁾ Practically the current is limited by the overall system design including the customer-specific PCB.

²⁾ The parameter is not subject to production test - verified by design/characterization.

³⁾ The product can operate at a specified current based on best practice to minimize electro-migration at the solder joint. For rare events and inrush currents, the value may be exceeded.

⁴⁾ Device on a four-layer 2s2p FR4 PCB defined in accordance with JEDEC standards (JESD51-5-7). PCB is vertical in still air.



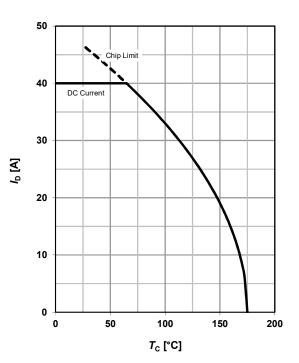
1 Power dissipation

$$P_{\text{tot}}$$
 = f(T_{C}); V_{GS} = 10 V

70 60 50 40 20 10 0 0 50 100 150 200 T_C [°C]

2 Drain current

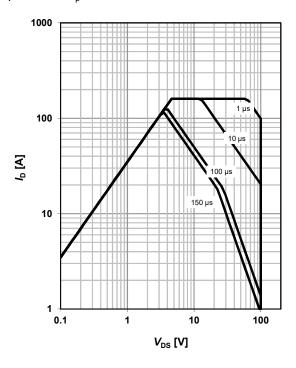
$$I_{\rm D} = f(T_{\rm C}); V_{\rm GS} = 10 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

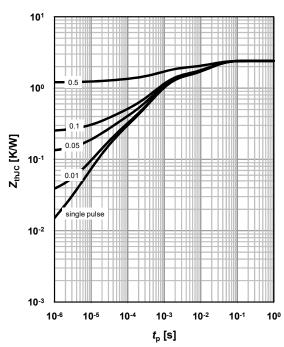
parameter: $t_{\rm p}$



4 Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$

parameter: $D = t_p/T$





5 Typ. output characteristics

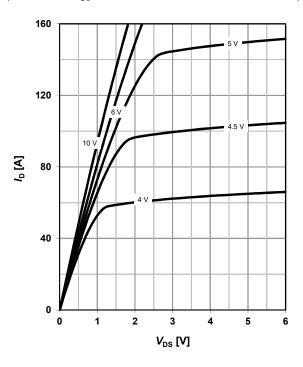
 $I_D = f(V_{DS}); T_j = 25 °C$

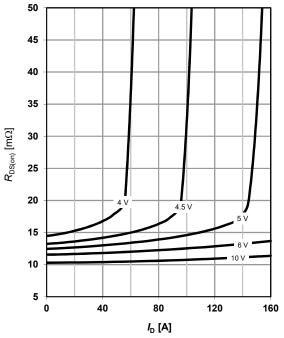
parameter: $V_{\rm GS}$

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

parameter: V_{GS}





7 Typ. transfer characteristics

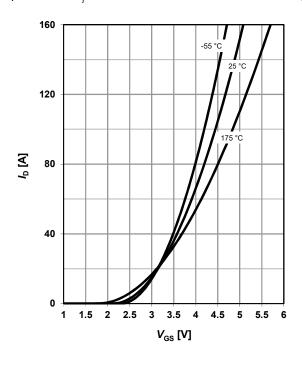
 $I_D = f(V_{GS}); V_{DS} = 6V$

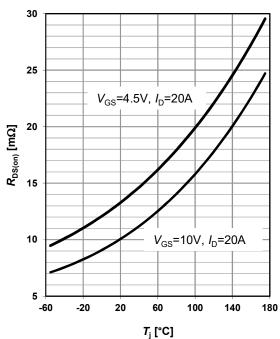
parameter: $T_{\rm j}$

8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_i);$

parameter: I_{D,} V_{GS}







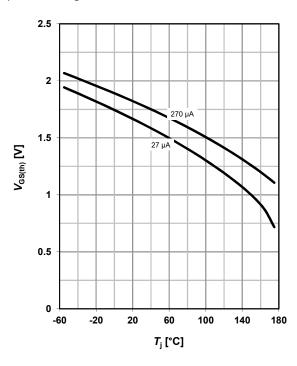
9 Typ. gate threshold voltage

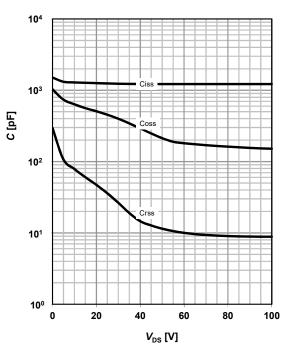
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristics

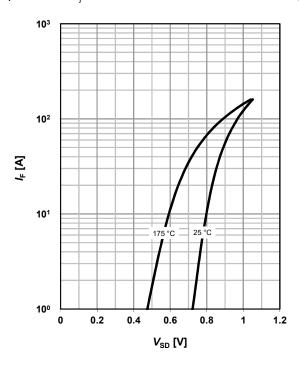
 $I_F = f(V_{SD})$

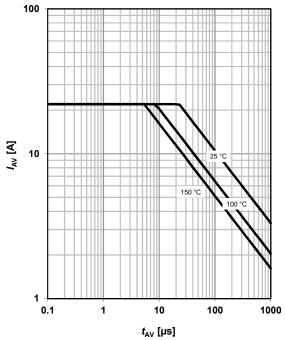
parameter: $T_{\rm j}$

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







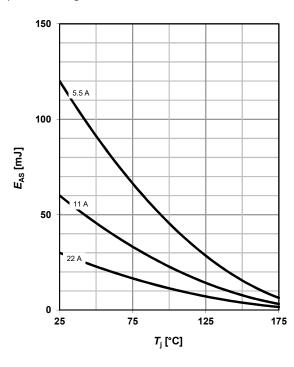
13 Avalanche energy

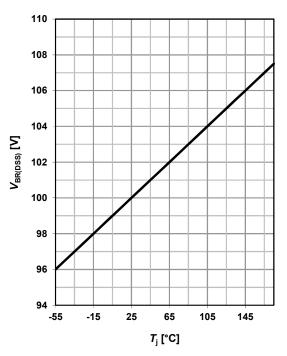
 $E_{AS} = f(T_j)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

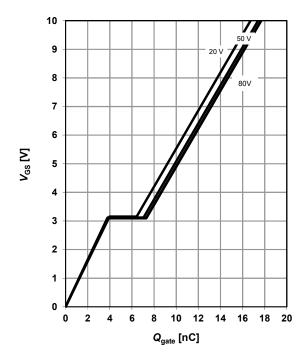




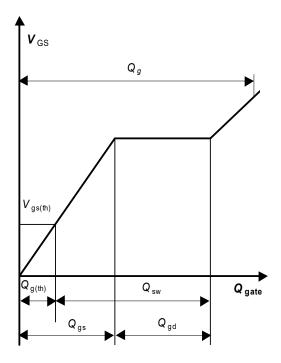
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 20 A pulsed$

parameter: $V_{\rm DD}$

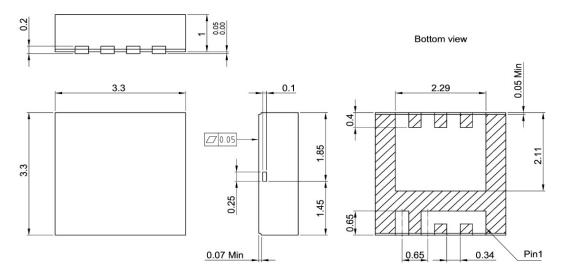


16 Gate charge waveforms



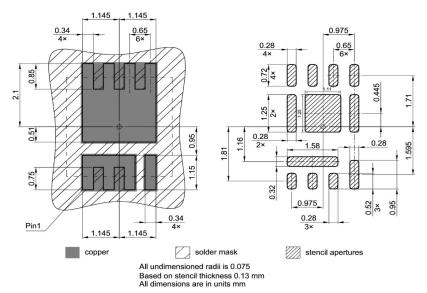


Package Outline

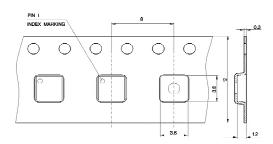


All dimensions are in units mm
The drawing is in compliance with ISO 128-30, Projection Method 1 [

Footprint



Packaging





Published by Infineon Technologies AG 81726 Munich, Germany

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Revision History

Version	Date	Changes
Revision 1.0	2021-05-14	Final Data Sheet
Revision 1.1	2021-06-18	Datasheet file name updated